

# INTERNATIONAL STANDARD

## NORME INTERNATIONALE



**Electronics assembly technology –  
Part 3: Selection guidance of environmental and endurance test methods for  
solder joints**

**Techniques d'assemblage des composants électroniques –  
Partie 3: Guide de choix des méthodes d'essai d'environnement et d'endurance  
des joints brasés**



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**ELECTRONICS ASSEMBLY TECHNOLOGY –****Part 3: Selection guidance of environmental and endurance test methods for solder joints**

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International Standard IEC 62137-3 has been prepared by IEC technical committee 91: Electronics assembly technology.

This first edition cancels and replaces IEC/PAS 62137-3, published in 2008, and includes some editorial revisions. The main changes with respect to the PAS include the following:

- no technical changes;
- some editorial changes and corrections;
- for the sake of convenience some constitutive changes.

The text of this standard is based on the following documents:

FDIS	Report on voting
91/986/FDIS	91/1011/RVD

Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

A list of all parts of IEC 62137 under the general title *Electronics assembly technology* can be found in the IEC website.

Future standards in this series will carry the new general title as cited above. Titles of existing standards in this series will be updated at the time of the next edition.

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## ELECTRONICS ASSEMBLY TECHNOLOGY –

### Part 3: Selection guidance of environmental and endurance test methods for solder joints

#### 1 Scope

This part of IEC 62137 describes the selection methodology of an appropriate test method for a reliability test for solder joints of various shapes and types of surface mount devices (SMD), array type devices and leaded devices, and lead insertion type devices using various types of solder material alloys.

#### 2 Normative references

The following referenced documents are indispensable for the application of this document. For a dated reference, only the edition cited applies. For an undated reference, the latest edition of the referenced document (including any amendment) applies.

IEC 60194, *Printed board design, manufacture and assembly – Terms and definitions*

IEC 61188-5 (all parts), *Printed boards and printed board assemblies – Design and use*

IEC 61249-2-7, *Materials for printed boards and other interconnecting structures – Part 2-7: Reinforced base materials clad and unclad – Epoxide woven E-glass laminated sheet of defined flammability (vertical burning test), copper-clad*

IEC 62137-1-1:2007, *Surface mounting technology – Environmental and endurance test methods for surface mount solder joint – Part 1-1: Pull strength test*

IEC 62137-1-2:2007, *Surface mounting technology – Environmental and endurance test methods for surface mount solder joint – Part 1-2: Shear strength test*

IEC 62137-1-3:2008, *Surface mounting technology – Environmental and endurance test methods for surface mount solder joint – Part 1-3: Cyclic drop test*

IEC 62137-1-4:2009, *Surface mounting technology – Environmental and endurance test methods for surface mount solder joint – Part 1-4: Cyclic bending test*

IEC 62137-1-5:2009, *Surface mounting technology – Environmental and endurance test methods for surface mount solder joints – Part 1-5: Mechanical shear fatigue test*

#### 3 Terms and definitions

For the purposes of this document, the terms and definitions in IEC 60194, as well as the following, apply.

##### 3.1

##### **pull strength for SMD**

maximum force to break the joint of a lead to substrate when a gull-wing lead of a surface mount device is pulled using a pulling tool at an angle of 45° to the substrate surface

[IEC 62137-1-1:2007, modified]